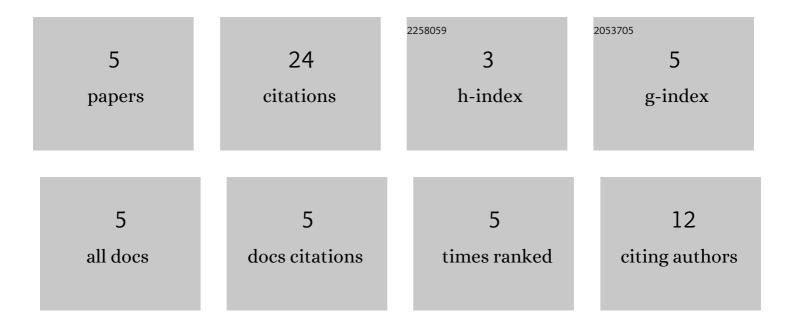
Ryosuke Okuyama

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Reduction of Dark Current in CMOS Image Sensor Pixels Using Hydrocarbon-Molecular-Ion-Implanted Double Epitaxial Si Wafers. Sensors, 2020, 20, 6620.	3.8	9
2	Gettering Sinks for Metallic Impurities Formed by Carbon-Cluster Ion Implantation in Epitaxial Silicon Wafers for CMOS Image Sensor. IEEE Journal of the Electron Devices Society, 2018, 6, 1200-1206.	2.1	6
3	Molecular and Atomic Hydrogen Diffusion Behavior by Reaction Kinetic Analysis in Projection Range of Hydrocarbon Molecular Ion for CMOS Image Sensors. Physica Status Solidi (A) Applications and Materials Science, 2019, 216, 1900175.	1.8	5
4	Proximity gettering design of silicon wafers using silicon hydride and hydrocarbon mixture molecular ion implantation technique. Materials Science in Semiconductor Processing, 2021, 135, 106063.	4.0	3
5	Hydrogen diffusion behavior in CH2P-molecular-ion-implanted silicon wafers for CMOS image sensors. Materials Science in Semiconductor Processing, 2022, 137, 106211.	4.0	1